

10/506718

## UNITED STATES RECEIVING OFFICE (RO/US)

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| Re                        | International Appln. No. PCT/NL03/00171               |
| International Filing Date | 07 March 2003<br>(07.03.2003)                         |
| Applicant                 | RADDER, Arjen, Martijn et al.                         |
| Title of Invention        | METHOD FOR MEASURING PARAMETERS AND A STRIKING DEVICE |
| Agent's File              | R76.12-0001   |

## INFORMATION DISCLOSURE STATEMENT

Mail Stop PCT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

The patents or publications listed on the enclosed PTO Form-1449 are submitted pursuant to 37 C.F.R. § 1.97. Copies of the patents or publications cited are enclosed.

Submitted herewith is a copy (with English translation as appropriate) of an Official Search Report of the European Patent Office in counterpart foreign application No. PCT/NL03/00171 filed 07 March 2003.

Respectfully submitted,

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| FORM PTO-1449   | Atty. Docket No.: <b>10/506718</b> | App. No.:  |
| LIST OF PATENTS AND PUBLICATIONS FOR<br>APPLICANT'S INFORMATION<br>DISCLOSURE STATEMENT | First Named Inventor:              |            |
|   |                                    |            |
|   | Filing Date                        | Group Art: |
|   |                                    |            |

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| Examiner Initial | Document No. | Date      | Name    | Class          | Sub Class | Filing Date If Appropriate |
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|                  | AK           |           |         |                |           |                            |

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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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|  | AQ |  |
|  | AR |  |

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| EXAMINER: | DATE CONSIDERED: |
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.